

DDC2K200 is a unique discrete device DC test module developed by SineTest Technologies. It integrates high voltage and large current in a single module (**patented**). One DDC2K200 module can complete all DC test items of a single Mosfet/IGBT within 2000V/200A, currently the only one in this industry. Configuring multiple DDC2K200s allows for true parallel testing of multi-sites (wafer test) or Index-parallel testing (final test), making it efficient and economical with best COT(cost of test).

- Single module supports single, dual, and quad-die discrete device test
- Supports both N-type and P-type
- High-speed testing
- Current range (force & measure): 0.3 μ A to 200A, 10 levels
- Low voltage range (force & measure): 0V to 40V, 4 levels
- High voltage range (force & measure): 40V to 2000V, 3 levels
- Supports waveform capture and display
- Can be set to multi-site parallel test mode
- Three-channel low voltage high current source (PVI) and one-channel high voltage source (HVI)
- Occupies two slots
- $R_{dson} < 0.1m\Omega$ (current $> 5A$ and good contact)
- Leakage current less than 3nA
- Capable of plotting product characteristic curves

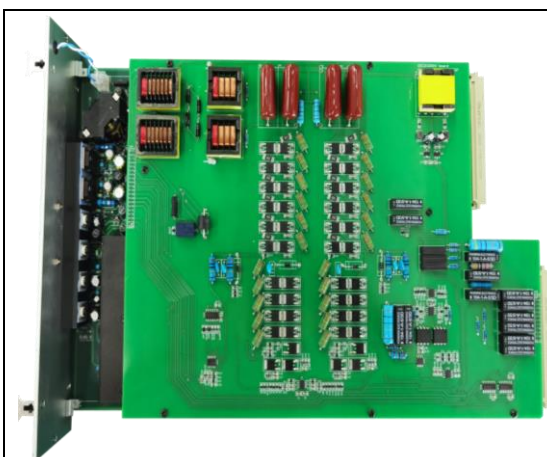
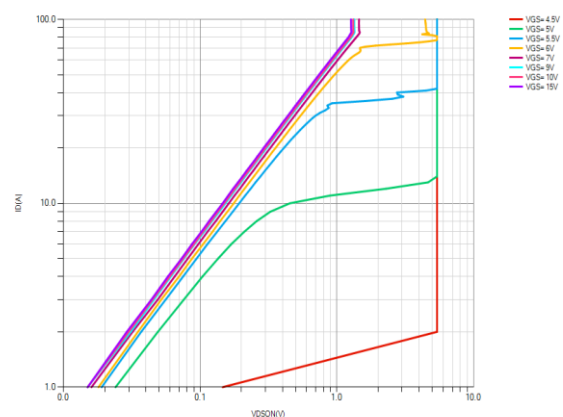


Photo of DDC2K200



C-V Curve (Vdson)

Advanced user also can enter the debug mode of DDC2K200, you can find the whole test circuit and set different test conditions to see the waveform, finally you can set the suitable delay time to get the stable result with highest UPH.

Following is the RDSON debug mode as sample:

